Search Notes



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09/839,471 Examiner

Michael Cuff

Applicant(s)/Patent under Reexamination

KEIL, DEAN S.

Art Unit

3627

SEARCHED					
Class	Subclass	Date	Examiner		
705	21	3/16/2007	МС		
705	16	3/16/2007	МС		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
705	21	3/16/2007	мс		
705	16	3/16/2007	мс		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Updated foreign and US patent text search, see notes	2/27/2007	MC		
Foreign text search, see notes	2/27/2007	MC		
Dialog search for all core business methods databases	2/27/2007	MC		
EIC, full template serch	2/7/2007	МС		
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